

600V Super-Junction Power MOSFET

DESCRIPTION

600V Super-junction Power MOSFET

Super-junction power MOSFET is a revolutionary technology for high voltage power MOSFETs, designed according to the SJ principle and pioneered. The Multi-EPI SJ MOSFET provide an extremely fast and robust body diode. Also provide an extremely low switching, communication and conduction losses device with highest robustness make especially resonant switching applications more reliable, more efficient, lighter and cooler, designed by Wuxi Unigroup Microelectronics Company.

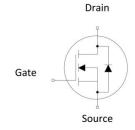
FEATURES

- Ultra-fast body diode
- Very low FOM $R_{DS(on)} \times Q_a$
- Easy to use/drive
- 100% avalanche tested
- RoHS compliant

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Power Factor Correction (PFC)
- LLC Half-bridge
- Charger







Device Marking and Package Information

Device	Package	Marking	
TPA60R360MFD	TO-220F	60R360MFD	

Key Performance Parameters

Rey Performance Parameters				
Parameter	Value	Unit		
V _{DS} @ T _{j,max}	600	V		
R _{DS(on),max}	0.36	Ω		
I _D	11	A		
$Q_{g,typ}$	20.5	nC		
I _{DM}	33	A		
t _{rr}	119	ns		
Q _{rr}	0.58	μC		
I _{rrm}	9.8	А		



Absolute Maximum Ratings T _C = 25°C, unless otherwise noted				
Parameter		Symbol	Value	Unit
Drain-Source Voltage (V _{GS} = 0V)		V _{DSS}	600	V
Continuous Drain Current	T _C = 25°C		11	А
Continuous Brain Current	TC = 100°C	l _D	6.6	
Pulsed Drain Current	(note1)	I _{DM}	33	А
Gate-Source Voltage		V_{GSS}	±30	V
Single Pulse Avalanche Energy	(note2)	E _{AS}	210	mJ
Repetitive Avalanche Energy	(note2)	E _{AR}	0.32	mJ
Avalanche Current		I _{AR}	1.8	А
MOSFET dv/dt ruggedness, V _{DS} = 0480V		dv/dt	50	V/ns
Power Dissipation		P_{D}	31	W
Continuous Body Diode Current		Is	11	A
Pulsed Diode Forward Current (note1)		I _{SM}	33	
Reverse diode dv/dt (note3)		dv/dt	50	V/ns
Maximum diode commutation speed (note3)		di _f /dt	900	A/us
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55~+150	°C

Thermal Resistance			
Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	R _{thJC}	4	°C/W
Thermal Resistance, Junction-to-Ambient	R_{thJA}	80	C/VV



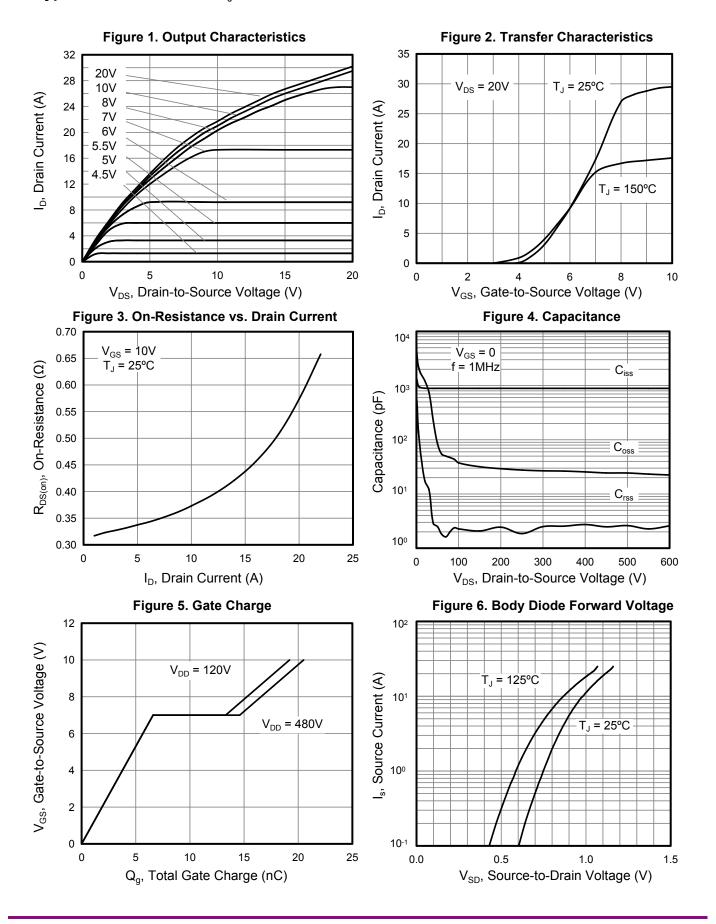
Douguestou			Value				
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	600			V	
7 0 1 1/1 5 1 0 1		$V_{DS} = 600V$, $V_{GS} = 0V$, $T_{J} = 25$ °C			1.25		
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 600V, V _{GS} = 0V, T _J = 150°C			1250	μΑ	
Gate-Source Leakage	I _{GSS}	V_{GS} = $\pm 30V$			±100	nA	
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3		5	V	
Drain-Source On-Resistance	R _{DS(on)}	V _{GS} = 10V, I _D = 5.5A		0.33	0.36	Ω	
Gate resistance	R_{G}	f = 1.0MHz open drain		18		Ω	
Dynamic	'			Į.			
Input Capacitance	C_{iss}	\/ O\/		890		pF	
Output Capacitance	C _{oss}	$V_{GS} = 0V,$ $V_{DS} = 100V,$		38			
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		2			
Total Gate Charge	Q_g			20.5		nC	
Gate-Source Charge	Q_{gs}	$V_{DD} = 480V, I_{D} = 11A,$ $V_{GS} = 10V$		6.6			
Gate-Drain Charge	Q_{gd}			8.0			
Turn-on Delay Time	t _{d(on)}			23			
Turn-on Rise Time	t _r	V _{DD} = 400V, I _D = 11A,		22			
Turn-off Delay Time	t _{d(off)}	$R_G = 25\Omega$		94		ns	
Turn-off Fall Time	t _f			26			
Drain-Source Body Diode Characte	eristics						
Body Diode Voltage	V _{SD}	$T_J = 25^{\circ}\text{C}, I_{SD} = 5.5\text{A}, V_{GS} = 0\text{V}$		1.0	1.5	V	
Reverse Recovery Time	t _{rr}			119		ns	
Reverse Recovery Charge	Q_{rr}	$V_R = 400V, I_F = I_S,$ $di_F/dt = 100A/\mu s$		0.58		μC	
Peak Reverse Recovery Current	I _{rrm}	317/30 100/140		9.8		Α	

Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. I_{AS} = 1.8A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25 $^{\circ}$ C
- 3. Identical low side and high side switch with identical $R_{\mbox{\scriptsize G}}$



Typical Characteristics $T_J = 25^{\circ}\text{C}$, unless otherwise noted





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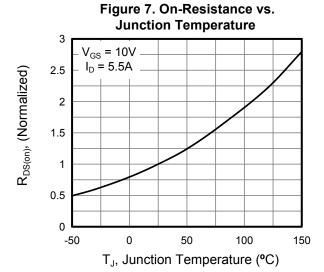


Figure 9. Transient Thermal Impedance TO-220F

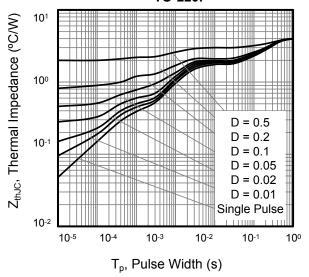


Figure 8. Breakdown voltage vs. Junction Temperature

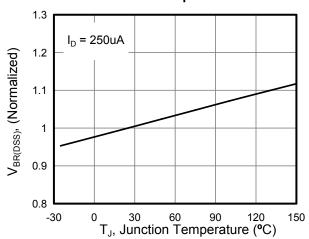


Figure 10. Safe operation area for TO-220F

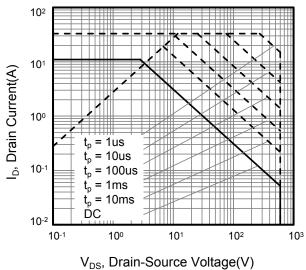




Figure A: Gate Charge Test Circuit and Waveform

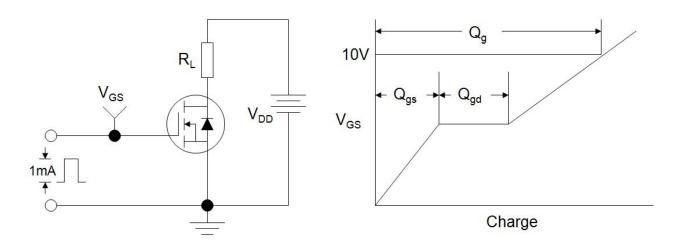


Figure B: Resistive Switching Test Circuit and Waveform

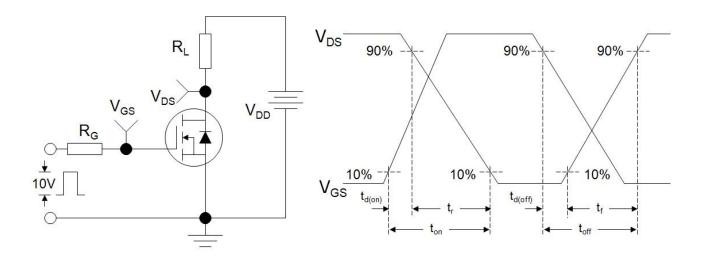
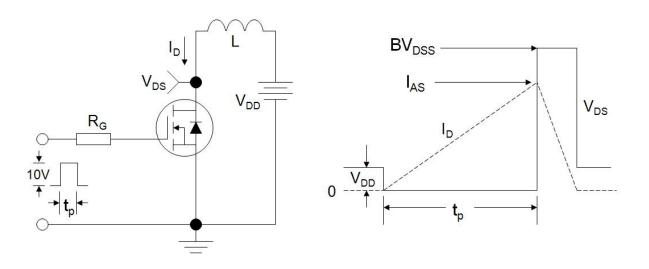
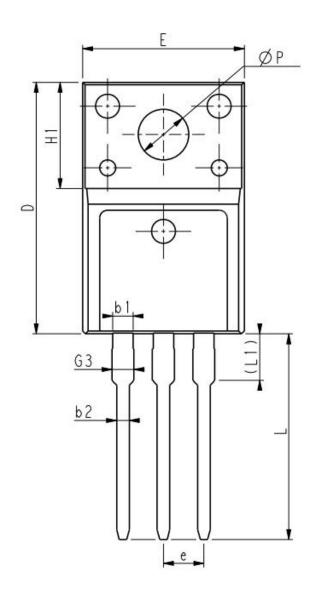


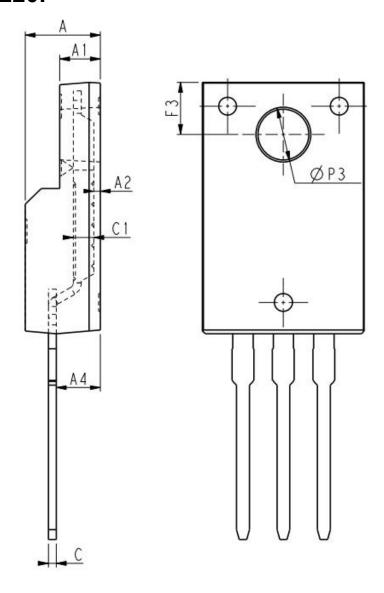
Figure C: Unclamped Inductive Switching Test Circuit and Waveform





TO-220F





Unit:mm				
Symbol	Min.	Nom	Max.	
E	9.96	10.16	10.36	
Α	4.50	4.70	4.90	
A1	2.34	2.54	2.74	
A2	0.30	0.45	0.60	
A4	2.56	2.76	2.96	
С	0.40	0.50	0.65	
c1	1.20	1.30	1.35	
D	15.57	15.87	16.17	
H1	6.70REF			

Unit:mm				
Symbol	Min.	Nom	Max.	
е		2.54BSC		
L	12.68	12.98	13.28	
L1	2.93	3.03	3.13	
ФР	3.03	3.18	3.38	
ФР3	3.15	3.45	3.65	
F3	3.15	3.30	3.45	
G3	1.25	1.35	1.55	
b1	1.18	1.28	1.43	
b2	0.70	0.80	0.95	



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